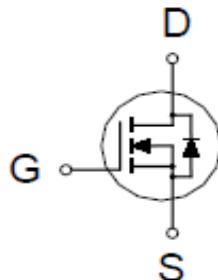
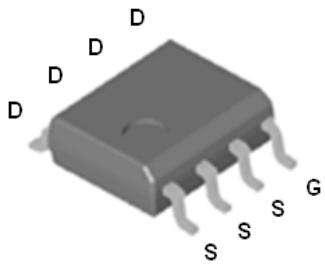


P8008BVA

N-Channel Enhancement Mode MOSFET

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
80V	68mΩ @ $V_{GS} = 10V$	3.5A



SOP-8

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	80	V
Gate-Source Voltage	V_{GS}	± 25	
Continuous Drain Current $T_A = 25^\circ C$	I_D	3.5	A
		2.8	
Pulsed Drain Current ¹	I_{DM}	14	
Avalanche Current	I_{AS}	14.7	
Avalanche Energy	E_{AS}	10.8	mJ
Power Dissipation $T_A = 25^\circ C$	P_D	1.8	W
		1.1	
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient	$R_{\theta JA}$		69	°C / W
Junction-to-Lead	$R_{\theta JL}$		25	

¹Pulse width limited by maximum junction temperature.

P8008BVA

N-Channel Enhancement Mode MOSFET

ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNITS	
			MIN	TYP	MAX		
STATIC							
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	80			V	
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	1.3	1.8	2.3		
Gate-Body Leakage	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 25\text{V}$			± 100	nA	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = 64\text{V}, V_{\text{GS}} = 0\text{V}$			1	μA	
		$V_{\text{DS}} = 64\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 70^\circ\text{C}$			10		
Drain-Source On-State Resistance ¹	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = 4.5\text{V}, I_D = 1\text{A}$		47	78	$\text{m}\Omega$	
		$V_{\text{GS}} = 10\text{V}, I_D = 3\text{A}$		44	68		
Forward Transconductance ¹	g_{fs}	$V_{\text{DS}} = 10\text{V}, I_D = 3\text{A}$		17		S	
DYNAMIC							
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 25\text{V}, f = 1\text{MHz}$		562		pF	
Output Capacitance	C_{oss}			63			
Reverse Transfer Capacitance	C_{rss}			38			
Gate Resistance	R_g	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 0\text{V}, f = 1\text{MHz}$		1.2		Ω	
Total Gate Charge ² (10V)	Q_g	$V_{\text{DS}} = 80\text{V}, I_D = 3\text{A}, V_{\text{GS}} = 10\text{V}$		14		nC	
Total Gate Charge ² (4.5V)	Q_g			8			
Gate-Source Charge ²	Q_{gs}			2			
Gate-Drain Charge ²	Q_{gd}			4.5			
Turn-On Delay Time ²	$t_{\text{d}(\text{on})}$	$V_{\text{DS}} = 40\text{V}, I_D \geq 3\text{A}, V_{\text{GS}} = 10\text{V}, R_G = 6\Omega$		15		nS	
Rise Time ²	t_r			14			
Turn-Off Delay Time ²	$t_{\text{d}(\text{off})}$			38			
Fall Time ²	t_f			17			
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS							
Continuous Current	I_S				1.4	A	
Forward Voltage ¹	V_{SD}	$I_F = 3\text{A}, V_{\text{GS}} = 0\text{V}$			1.3	V	
Reverse Recovery Time	t_{rr}	$I_F = 3\text{A}, dI_F/dt = 100\text{A}/\mu\text{s}$		17		nS	
Reverse Recovery Charge	Q_{rr}			10		nC	

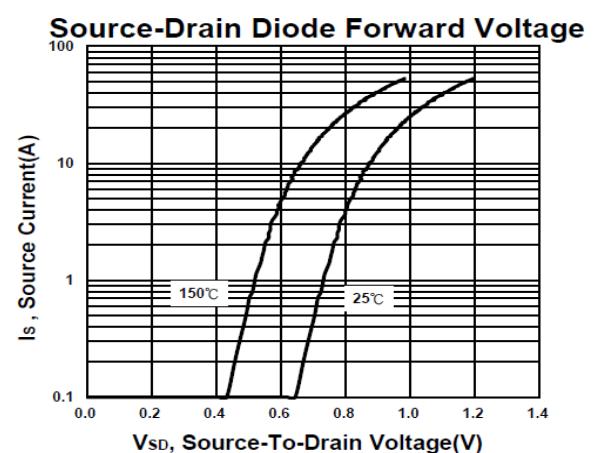
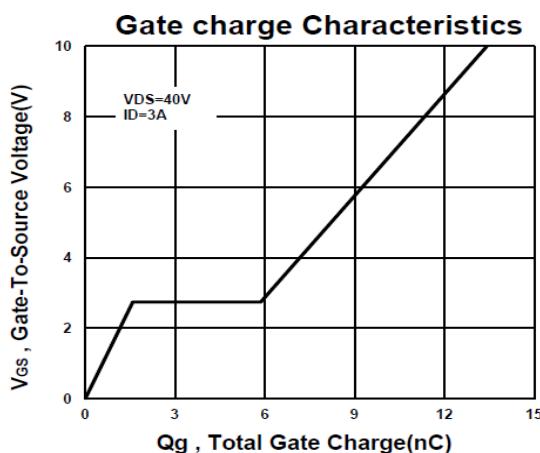
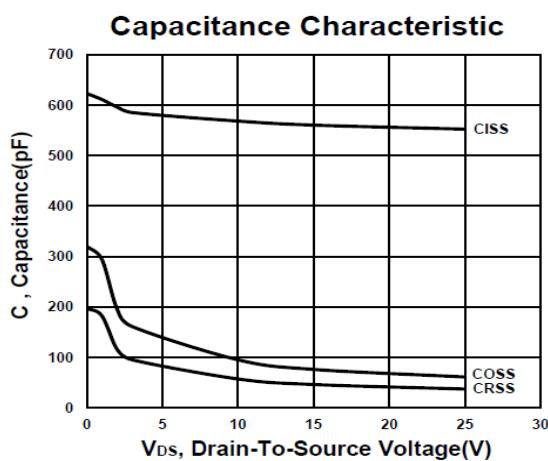
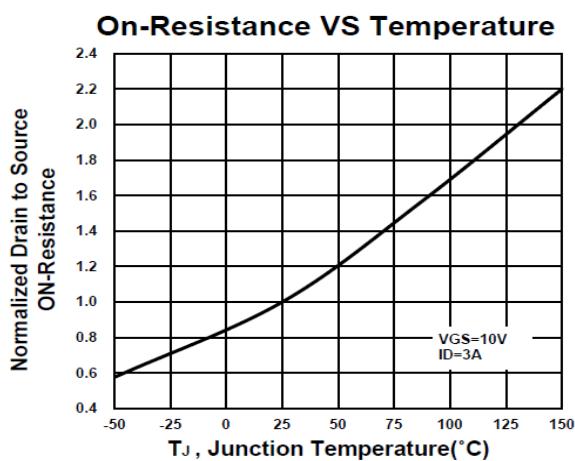
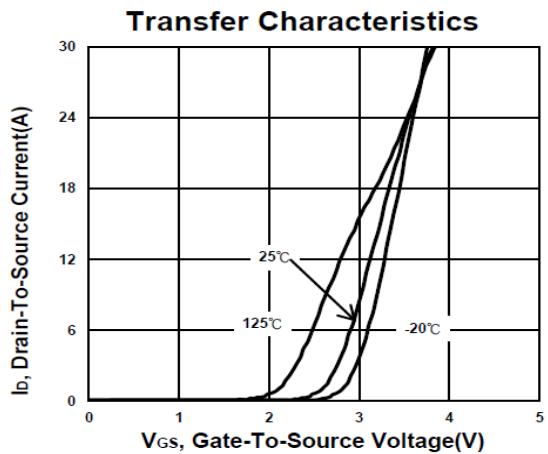
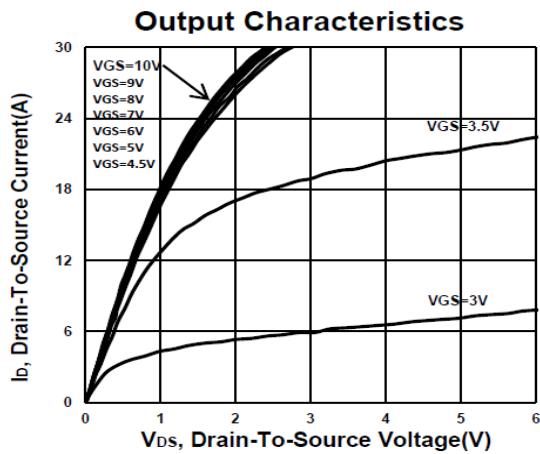
¹Pulse test : Pulse Width $\leq 300\ \mu\text{sec}$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

³Pulse width limited by maximum junction temperature.

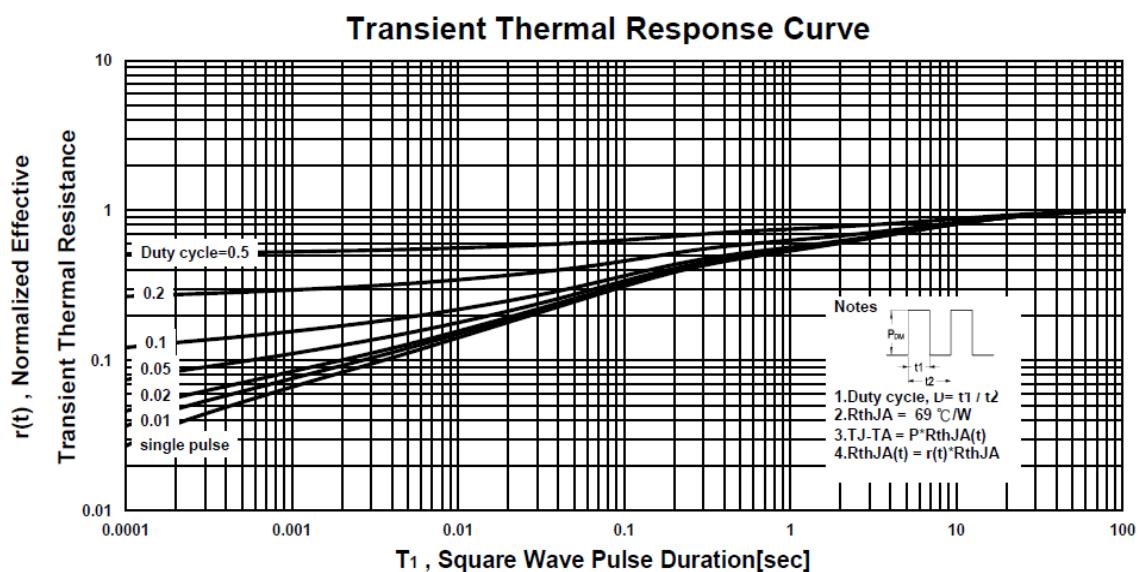
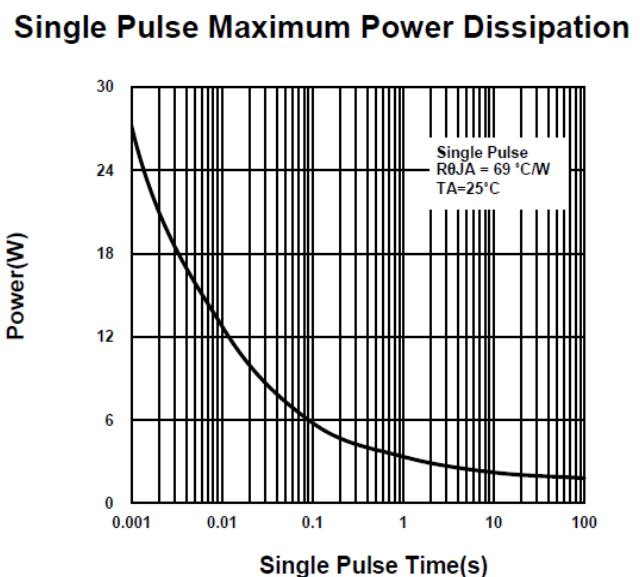
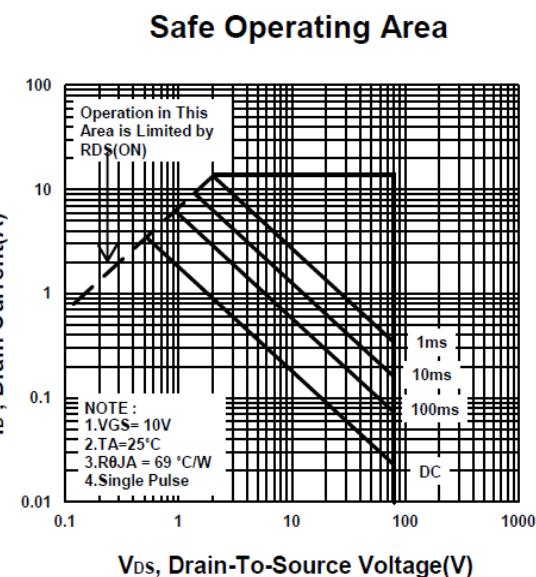
P8008BVA

N-Channel Enhancement Mode MOSFET



P8008BVA

N-Channel Enhancement Mode MOSFET



P8008BVA

N-Channel Logic Level Enhancement Mode MOSFET

Package Dimension

SOP-8 MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	4.8	4.9	5.0	H	0.4	0.6	0.93
B	3.8	3.9	4.0	I	0.19	0.21	0.25
C	5.79	6.0	6.2	J	0.25	0.375	0.5
D	0.33	0.4	0.51	K	0°	3°	18°
E	1.25	1.27	1.29				
F	1.1	1.3	1.65				
G	0.05	0.15	0.25				

